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Amendments to the Claims

This listing of claims will replace all prior versions and listings of claims in this application—including presently cancelled claims 66, 68, 69, amended claim 67, and added new claims 82-85.

Listing of Claims

Claim 1 (original): A semiconductor device comprising:
a layer of semiconductor material;
a thyristor formed in the layer of semi-conductor material;
the thyristor comprising at least one base-emitter junction; and
leakage species disposed in the semiconductor material and across the at least one base-emitter junction.

Claim 2 (original): The device of claim 1, in which the leakage species comprises carbon.

Claim 3 (original): The device of claim 2, in which the carbon comprises a density across the at least one base-emitter junction sufficient to establish a low-voltage leakage characteristic for the at least one base-emitter junction that is substantially greater than the leakage therefor absent the carbon.

Claim 4 (original): The device of claim 3, the low-voltage leakage characteristic greater than twice the leakage therefor absent the carbon.

Claim 5 (original): The device of claim 3, in which the low-voltage leakage characteristic is characterized across a bias region of less than 0.50 volts.

Record identified as claim of 2/01/05 with 12 pages seems to recite claims in conformity with 37 CFR § 1.121(d) as revealed in the PAIR records of 3/29/05 and as confirmed by phone conference with Examiner Wosieczkiewicz.

CKO

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